



WANSEMI
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WX012CN10LL

N-channel Enhancement Mode Power MOSFET

TOLL/100V/±20V/3.0V/263A/1.87mΩ

Rev0.5

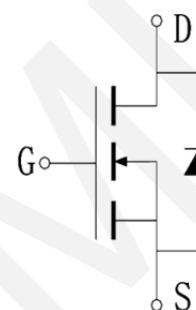


100V, 1.87mΩ, 263A, N-channel MOSFET

1. Features

- ◆ Excellent R_{DS(ON)} and Low Gate Charge
- ◆ 100% UIS Tested
- ◆ 100% ΔV_{Ds} Tested
- ◆ 100% RG Tested
- ◆ 100% DVDS Tested
- ◆ Halogen-free; RoHS-compliant

V _{DS}	R _{DS(on)} Typ.	I _D Max.
100V	1.87mΩ @10V	263



Schematic Diagram

TOLL
Pin Description

2. Applications

- ◆ Load Switch
- ◆ PWM Application
- ◆ Power Management

Part no.	Package	Marking	PCS/Reel	PCS/CTN.
WX012CN10LL	TOLL	012N10	2,000	16,000

3. Package Marking and Ordering Information

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V _{DSS}	100	V
Gate to Source Voltage	V _{GSS}	±20	V
Drain Current (DC) T C = 25°C	I _D	263	A
Drain Current (DC) T C = 100°C	I _D	166	A
Drain Current (Pulse), PW≤300μs	I _{DM}	1052	A
Avalanche Energy, Single Pulsed	E _{AS}	1332	mJ
Total Dissipation T C = 25°C	P _D	321	W
Total Dissipation T C = 100°C	P _D	128	W
Junction Temperature	T _j	150	°C
Storage Temperature	T _{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

**5.Thermal Resistance Ratings (Note 2)**

Parameter	Symbol	Value	Unit
Junction to Ambient	R _{θJA}	55	°C/W
Junction to case	R _{θJC}	0.39	°C/W

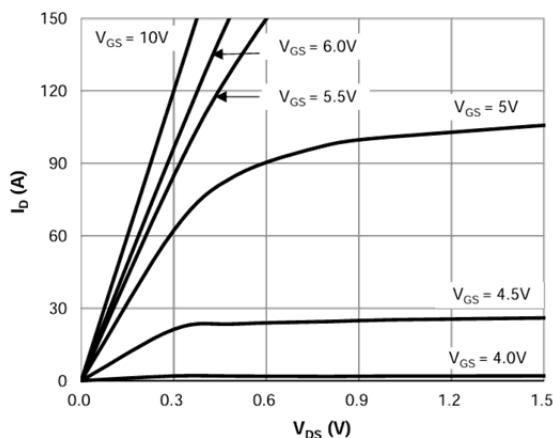
Note 2: When mounted on 1 inch square copper board t ≤ 10sec The value in any given application depends on the user's specific board design.

6.Electrical Characteristics at Ta=25°C (Note 2)

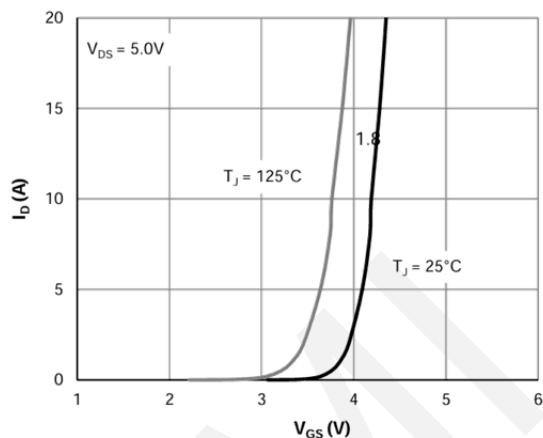
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	I _D = 250μA, V _{GS} = 0V	100	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} = 100V, V _{GS} = 0V	-	-	1	μA
Gate to Source Leakage Current	I _{GSS}	V _{GS} = ±20V, V _{DS} = 0V	-	-	±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	2.0	3.0	4.0	V
Static Drain to Source On-State Resistance	R _{DS(on)}	I _D =20A, V _{GS} =10V	-	1.87	2.1	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V, V _{DS} =50V, Frequency=1.0MHz	-	7260	-	pF
Output Capacitance	C _{oss}		-	2887	-	pF
Reverse Transfer Capacitance	C _{rss}		-	57	-	pF
Turn-on Delay Time	t _{d(on)}	V _{DS} = 50V, R _L =2.5Ω V _{GS} = 10V, R _{GEN} =6Ω	-	26	-	ns
Rise Time	t _r		-	43	-	ns
Turn-off Delay Time	t _{d(off)}		-	113	-	ns
Fall Time	t _f		-	64	-	ns
Total Gate Charge	Q _g	V _{DS} = 50V, V _{GS} =0 to 10V, I _D =20A	-	160	-	nC
	Q _{gs}		-	47	-	nC
	Q _{gd}		-	39	-	nC
Diode Forward Voltage	V _{FSD}	I _S = 20A, V _{GS} = 0	0.5	-	1.2	V

Note 2: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

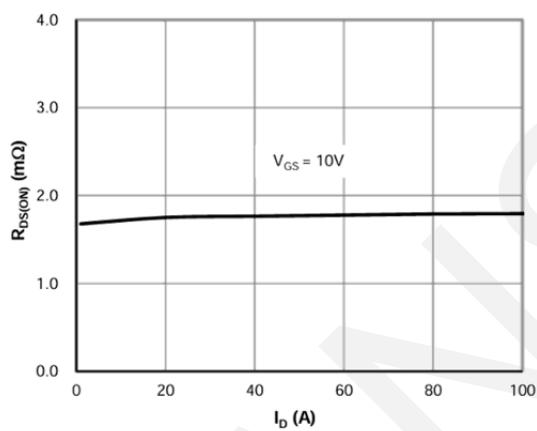
7.Typical electrical and thermal characteristics



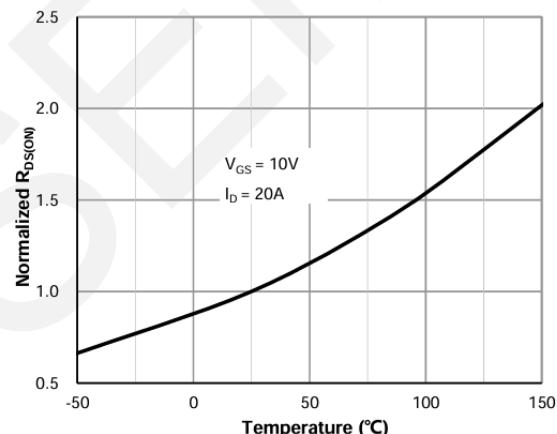
Saturation Characteristics



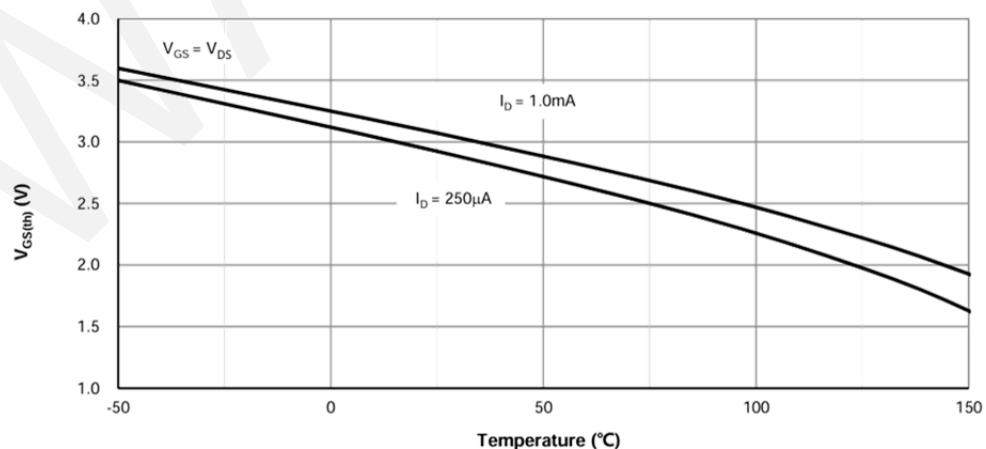
Transfer Characteristics



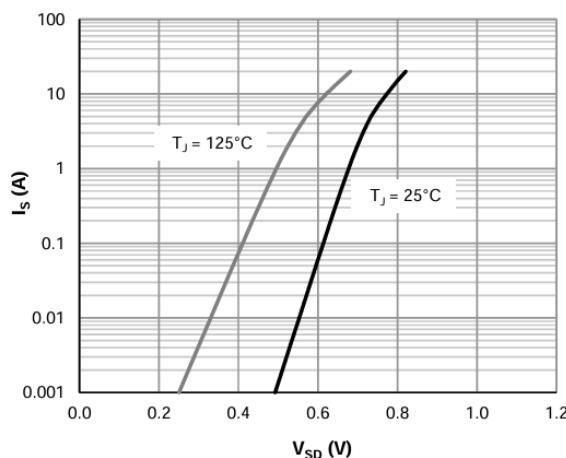
$R_{DS(on)}$ vs. Drain Current



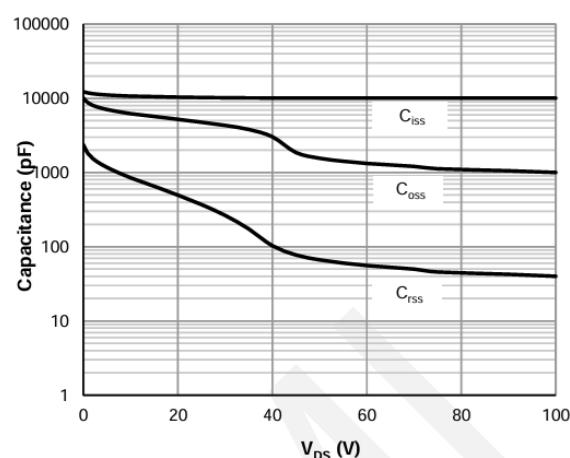
$R_{DS(ON)}$ vs. Junction Temperature



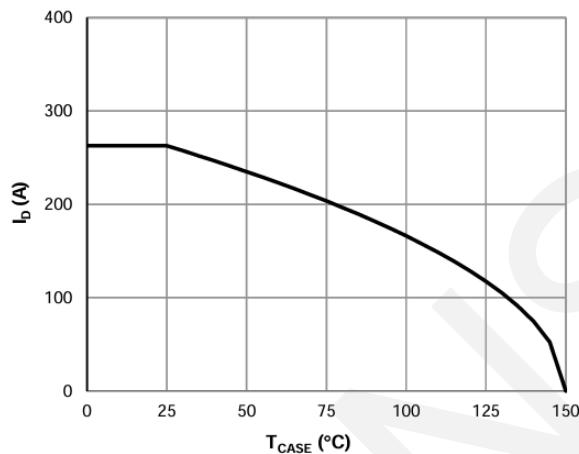
$V_{GS(th)}$ vs. Junction Temperature



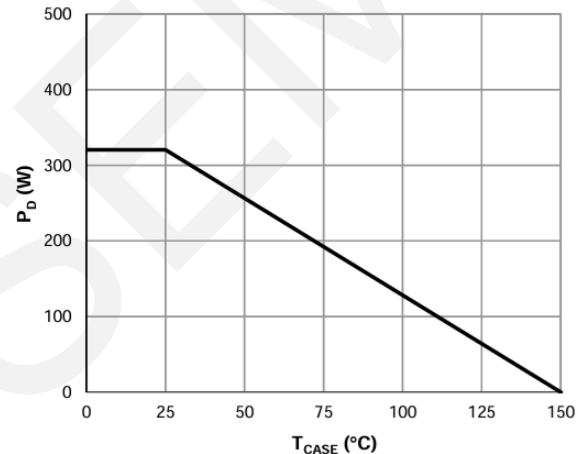
Body-Diode Characteristics



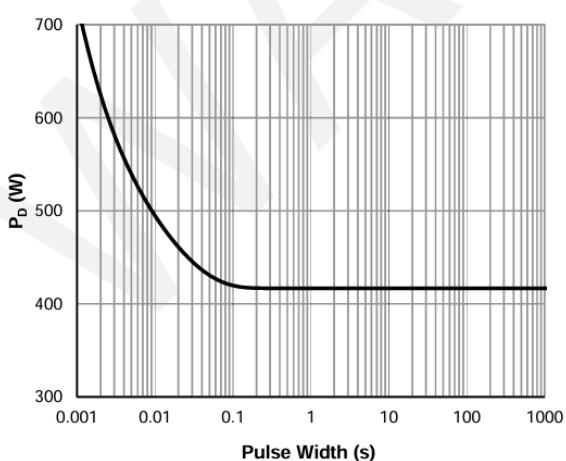
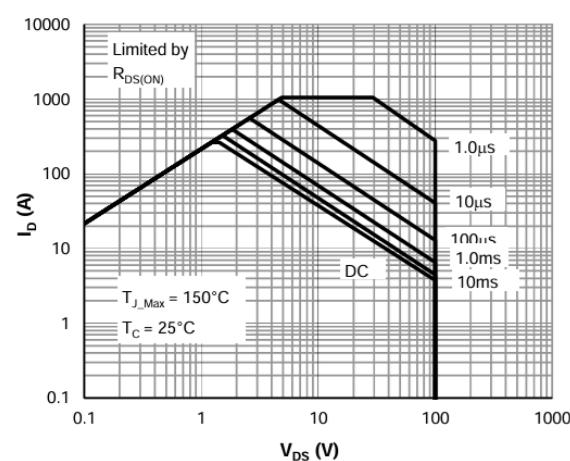
Capacitance Characteristics



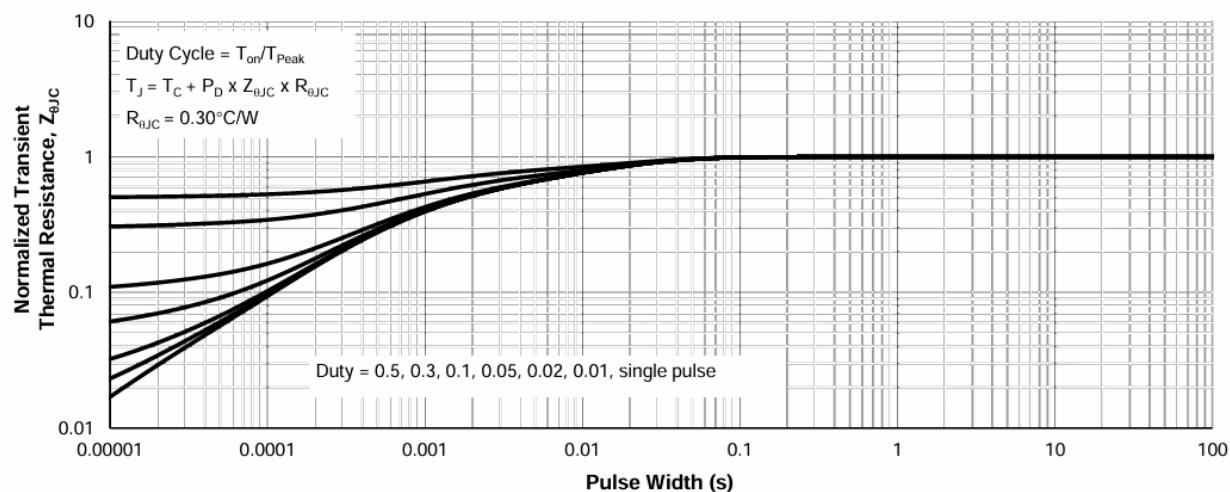
Current De-rating



Power De-rating

Single Pulse Power Rating,
Junction-to-Case

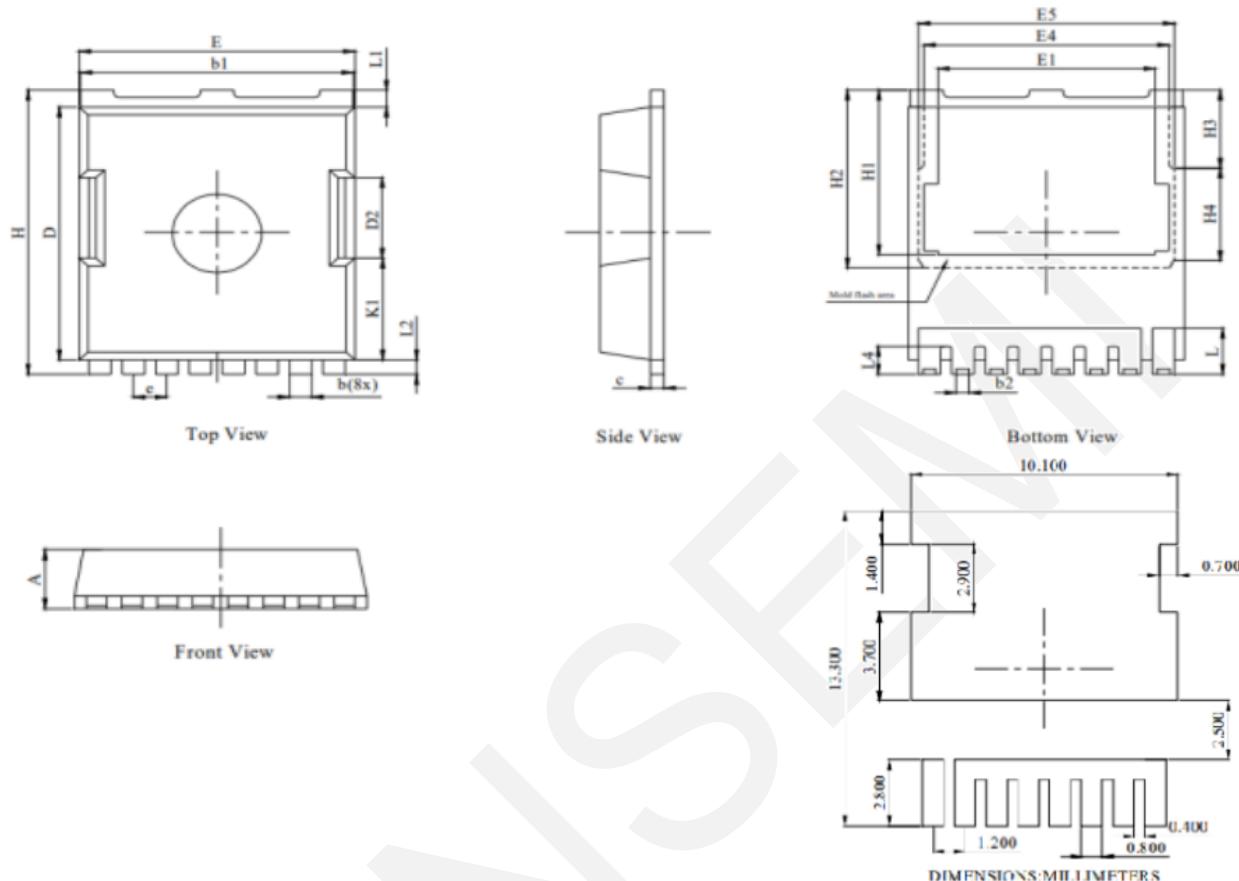
Maximum Safe Operating Area



Normalized Maximum Transient Thermal Impedance



8.Package Dimensions



DIM.	MILLIMETER		
	MIN	NOM	MAX
A	2.20	2.30	2.50
b	0.70	0.80	0.90
b1	9.70	9.80	9.90
b2	0.42	0.46	0.50
C	0.40	0.50	0.65
D	10.28	10.38	10.58
D2		3.30	
E	9.70	9.90	10.10
E1		7.80	
E4		8.80	
E5		9.20	
e	1.20(BSC)		
H	11.48	11.68	11.88
H1	6.55	6.75	6.85
H2		7.30	
H3		3.20	
H4		3.80	
K1		4.18	
L	1.70	1.90	2.10
L1		0.70	
L2		0.60	
L4	1.00	1.15	1.30

9. Important Notice

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